

# PC352NJ0000F Series

# Mini-flat Package, High CMR Photocoupler



## ■ Description

**PC352NJ0000F Series** contains an IRED optically coupled to a phototransistor.

It is packaged in a 4-pin Mini-flat.

Input-output isolation voltage(rms) is 3.75kV.

Collector-emitter voltage is 80V and CTR is 90% to 480% at input current of  $I_F$  5mA.

#### ■ Features

- 1. Mini-flat package
- 2. Double transfer mold package (Ideal for Flow Soldering)
- 3. High resistance to noise due to high common mode rejection voltage (CMR : MIN. 10kV/µs)
- 4. High collector-emitter voltage (V<sub>CEO</sub>: 80V)
- 5. High isolation voltage between input and output (V<sub>iso(rms)</sub>: 3.75kV)
- 6. Lead-free and RoHS directive compliant

## ■ Agency approvals/Compliance

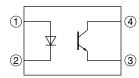
- 1. Recognized by UL1577 (Double protection isolation), file No. E64380 (as model No. **PC352**)
- 2. Package resin: UL flammability grade (94V-0)

## ■ Applications

1. Programmable controllers



## ■ Internal Connection Diagram



1 Anode

② Cathode 3 Emitter

4 Collector

## **■** Outline Dimensions

(Unit:mm) 3.6<sup>±0.3</sup> 2.54<sup>±0.25</sup> SHARP mark "s" Date code Anode mark 1 Rank mark Factory identification mark 0.4<sup>±0.1</sup>  $5.3^{\pm0.3}$ Epoxy resin 45° 0.2 ±0.05  $0.5^{+0.4}_{-0.2}$  $7.0^{+0.2}_{-0.7}$ Product mass: approx. 0.1g

Plating material: SnCu (Cu: TYP. 2%)



# Date code (2 digit)

	1st o	digit		2nd digit		
	Year of p	roduction		Month of production		
A.D.	Mark	A.D	Mark	Month	Mark	
1990	A	2002	P	January	1	
1991	В	2003	R	February	2	
1992	С	2004	S	March	3	
1993	D	2005	T	April	4	
1994	Е	2006	U	May	5	
1995	F	2007	V	June	6	
1996	Н	2008	W	July	7	
1997	J	2009	X	August	8	
1998	K	2010	A	September	9	
1999	L	2011	В	October	0	
2000	M	2012	С	November	N	
2001	N	:	:	December	D	

repeats in a 20 year cycle

# Factory identification mark

Factory identification Mark	Country of origin	
no mark	T	
	- Japan	
	Indonesia	
	China	

<sup>\*</sup> This factory marking is for identification purpose only. Please contact the local SHARP sales representative to see the actual status of the production.

## Rank mark

Refer to the Model Line-up table



**■** Absolute Maximum Ratings

	■ Absolute Maximum Ratings (T <sub>a</sub> =25°C)							
	Parameter	Symbol	Rating	Unit				
	Forward current	$I_{\mathrm{F}}$	50	mA				
Input	*1 Peak forward current	$I_{FM}$	1	A				
Inj	Reverse voltage	$V_R$	6	V				
	Power dissipation	P	70	mW				
	Collector-emitter voltage	$V_{CEO}$	80	V				
Output	Emitter-collector voltage	V <sub>ECO</sub>	6	V				
Out	Collector current	$I_{C}$	50	mA				
	Collector power dissipation	P <sub>C</sub>	150	mW				
Total power dissipation		P <sub>tot</sub>	170	mW				
Operating temperature		Topr	-30 to +100	°C				
Storage temperature		T <sub>stg</sub>	-40 to +125	°C				
*2 Isolation voltage		V <sub>iso (rms)</sub>	3.75	kV				
*3 6	Soldering temperature	T <sub>sol</sub>	260	°C				

<sup>\*1</sup> Pulse width≤100μs, Duty ratio : 0.001 \*2 40 to 60%RH, AC for 1 minute, f=60Hz \*3 For 10s

# **■** Electro-optical Characteristics

 $(T_a=25^{\circ}C)$ 

								$(1_a=25 \text{ C})$
	Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit
	Forward voltage		$V_F$	$I_F=20mA$	-	1.2	1.4	V
Lamust	Peak forward	Peak forward voltage		I <sub>FM</sub> =0.5A	-	_	3.0	V
Input	Reverse curre	nt	$I_R$	$V_R=4V$	-	-	10	μΑ
	Terminal capa	acitance	$C_t$	V=0, f=1kHz	_	30	200	pF
	Collector dark	current	$I_{CEO}$	$V_{CE}=50V, I_{F}=0$	-	_	100	nA
Output	Collector-emitter breakdown voltage		BV <sub>CEO</sub>	$I_{C}=0.1 \text{mA}, I_{F}=0$	80	_	_	V
	Emitter-collector breakdown voltage		BV <sub>ECO</sub>	$I_{E}=10\mu A, I_{F}=0$	6	_	_	V
	Collector current		$I_{C}$	$I_F=5mA$ , $V_{CE}=5V$	4.5	_	24	mA
	Collector-emitter saturation voltage		V <sub>CE (sat)</sub>	$I_F=20\text{mA}, I_C=1\text{mA}$	-	0.1	0.2	V
	Isolation resistance		$R_{ISO}$	DC500V, 40 to 60%RH	5×10 <sup>10</sup>	1×10 <sup>11</sup>	_	Ω
Transfer	Floating capacitance		$C_{\rm f}$	V=0, f=1MHz	_	0.6	1.0	pF
charac-	Cut-off frequency		$f_C$	$V_{CE}$ =5 $V$ , $I_{C}$ =2 $mA$ , $R_{L}$ =100 $\Omega$ , -3 $dB$	15	80	-	kHz
teristics		Rise time	$t_r$	V 2V I 2m A B 1000	-	4	18	μs
	Response time	Fall time	$t_{\rm f}$	$V_{CE}=2V$ , $I_{C}=2mA$ , $R_{L}=100\Omega$	_	5	20	μs
	Common mode rejection voltage		CMR	$\begin{split} T_{a} = & 25^{\circ}C,  R_{L} = & 470\Omega,  V_{CM} = 1.5 kV(peak) \\ I_{F} = & 0mA,  V_{CC} = 9V,  V_{np} = 100mV \end{split}$	10	_	-	kV/μs



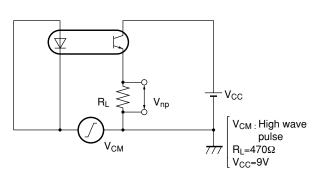
# **■** Model Line-up

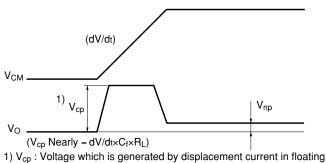
Package	Тар	oing	Rank mark	I <sub>C</sub> [mA]	
	3 000 pcs/reel 750 pcs/reel		Kalik iliaik	$(I_F=5mA, V_{CE}=5V, T_a=25^{\circ}C)$	
	PC352NJ0000F	PC352NTJ000F	with or without	4.5 to 24.0	
Model No.	PC352N1J000F	PC352N1TJ00F	A	4.5 to 9.0	
Wiodel No.	PC352N2J000F	PC352N2TJ00F	В	7.5 to 15.0	
	PC352N3J000F	PC352N3TJ00F	C	12.0 to 24.0	

Please contact a local SHARP sales representative to inquire about production status.



Fig.1 Test Circuit for Common Mode Rejection Voltae





capacitance between primary and secondary side.

Fig.2 Forward Current vs. Ambient **Temperature** 

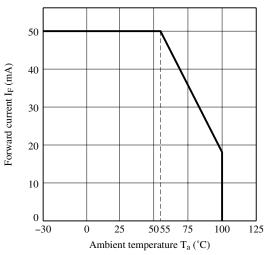


Fig.3 Diode Power Dissipation vs. Ambient **Temperature** 

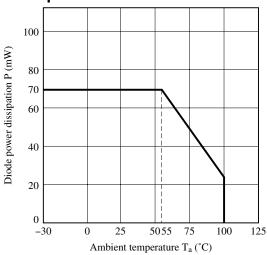


Fig.4 Collector Power Dissipation vs. **Ambient Temperature** 

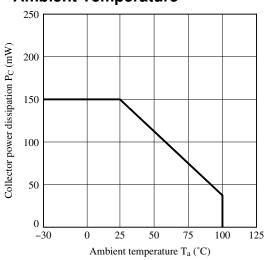
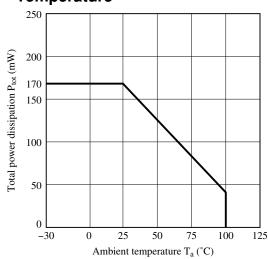


Fig.5 Total Power Dissipation vs. Ambient **Temperature** 





## Fig.6 Peak Forward Current vs. Duty Ratio

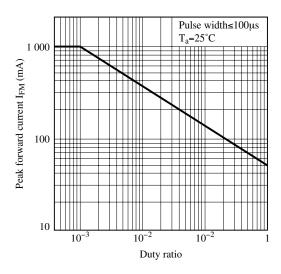


Fig.8 Current Transfer Ratio vs. Forward Current

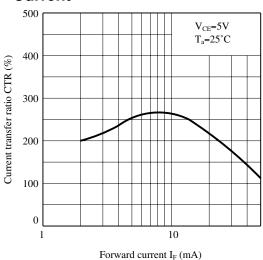


Fig.10 Relative Current Transfer Ratio vs.
Ambient Temperature

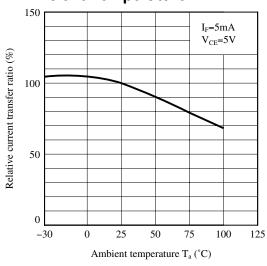


Fig.7 Forward Current vs. Forward Voltage

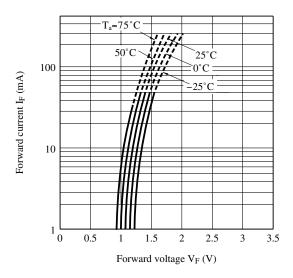


Fig.9 Collector Current vs. Collector-emitter Voltage

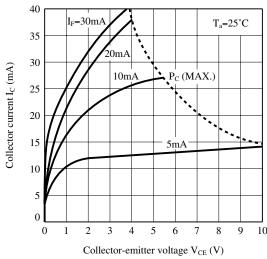


Fig.11 Collector - emitter Saturation Voltage vs. Ambient Temperature

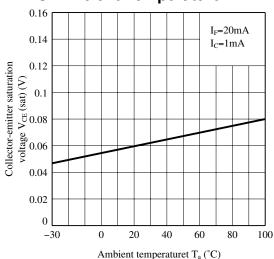




Fig.12 Collector Dark Current vs. Ambient Temperature

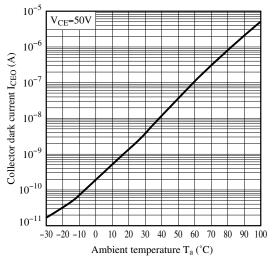
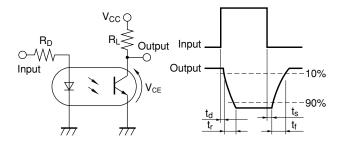


Fig.14 Test Circuit for Response Time



Please refer to the conditions in Fig.13

Fig.16 Collector-emitter Saturation Voltage vs. Forward Current

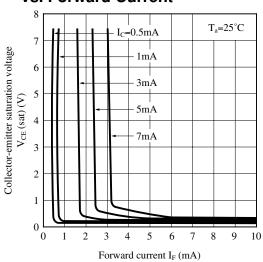


Fig.13 Response Time vs. Load Resistance

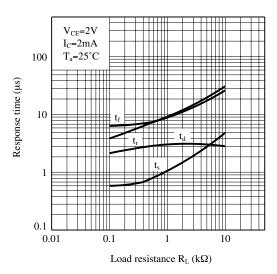
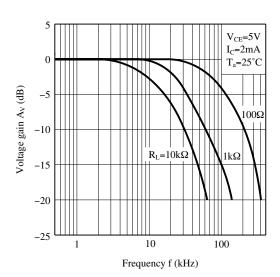


Fig.15 Frequency Response



Remarks : Please be aware that all data in the graph are just for reference and not for guarantee.



## **■ Design Considerations**

## Design guide

While operating at I<sub>F</sub><1.0mA, CTR variation may increase.

Please make design considering this fact.

In case that some sudden big noise caused by voltage variation is provided between primary and secondary terminals of photocoupler some current caused by it is floating capacitance may be generated and result in false operation since current may go through IRED or current may change.

If the photocoupler may be used under the circumstances where noise will be generated we recommend to use the bypass capacitors at the both ends of IRED.

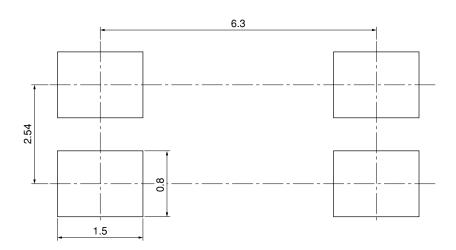
This product is not designed against irradiation and incorporates non-coherent IRED.

## Degradation

In general, the emission of the IRED used in photocouplers will degrade over time.

In the case of long term operation, please take the general IRED degradation (50% degradation over 5 years) into the design consideration.

#### Recommended Foot Print (reference)



Sheet No.: D2-A00202EN

(Unit: mm)

<sup>☆</sup> For additional design assistance, please review our corresponding Optoelectronic Application Notes.



## ■ Manufacturing Guidelines

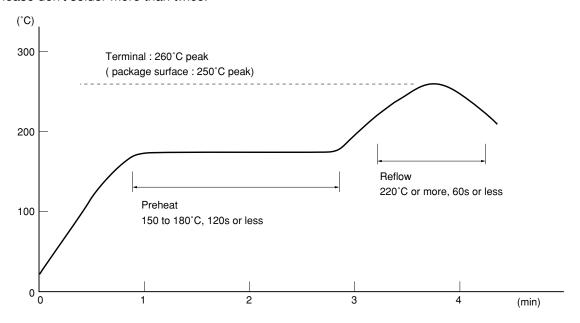
## Soldering Method

#### Reflow Soldering:

Reflow soldering should follow the temperature profile shown below.

Soldering should not exceed the curve of temperature profile and time.

Please don't solder more than twice.



## Flow Soldering:

Due to SHARP's double transfer mold construction submersion in flow solder bath is allowed under the below listed guidelines.

Flow soldering should be completed below 260°C and within 10s.

Preheating is within the bounds of 100 to 150°C and 30 to 80s.

Please don't solder more than twice.

#### Hand soldering

Hand soldering should be completed within 3s when the point of solder iron is below 400°C.

Please don't solder more than twice.

#### Other notices

Please test the soldering method in actual condition and make sure the soldering works fine, since the impact on the junction between the device and PCB varies depending on the tooling and soldering conditions.



## Cleaning instructions

#### Solvent cleaning:

Solvent temperature should be 45°C or below Immersion time should be 3 minutes or less

#### Ultrasonic cleaning:

The impact on the device varies depending on the size of the cleaning bath, ultrasonic output, cleaning time, size of PCB and mounting method of the device.

Therefore, please make sure the device withstands the ultrasonic cleaning in actual conditions in advance of mass production.

#### Recommended solvent materials:

Ethyl alcohol, Methyl alcohol and Isopropyl alcohol

In case the other type of solvent materials are intended to be used, please make sure they work fine in actual using conditions since some materials may erode the packaging resin.

#### Presence of ODC

This product shall not contain the following materials.

And they are not used in the production process for this product.

Regulation substances: CFCs, Halon, Carbon tetrachloride, 1.1.1-Trichloroethane (Methylchloroform)

Specific brominated flame retardants such as the PBBOs and PBBs are not used in this product at all.

This product shall not contain the following materials banned in the RoHS Directive (2002/95/EC).

•Lead, Mercury, Cadmium, Hexavalent chromium, Polybrominated biphenyls (PBB), Polybrominated diphenyl ethers (PBDE).



## ■ Package specification

# ● Tape and Reel package

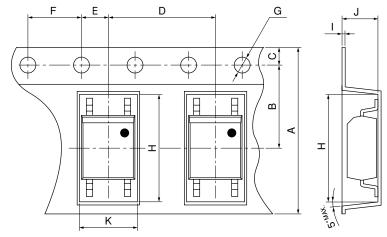
1. 3 000pcs/reel Package materials

Carrier tape: A-PET (with anti-static material)

Cover tape: PET (three layer system)

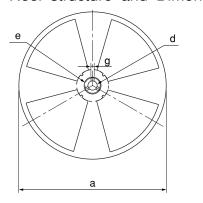
Reel: PS

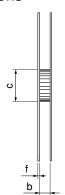
## Carrier tape structure and Dimensions



Dimension	(Unit: mm)					
A	В	C	D	Е	F	G
12.0 <sup>±0.3</sup>	5.5 <sup>±0.1</sup>	1.75 <sup>±0.1</sup>	8.0 <sup>±0.1</sup>	2.0 <sup>±0.1</sup>	4.0 <sup>±0.1</sup>	φ1.5 <del>+</del> 8.1
Н	I	J	K			
7.4 <sup>±0.1</sup>	0.3 <sup>±0.05</sup>	3.1 <sup>±0.1</sup>	4.0 <sup>±0.1</sup>			

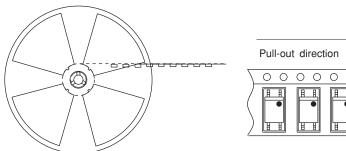
## Reel structure and Dimensions





Dimensio	ns List	(Unit: mm)		
a	b	c	d	
370	370 13.5±1.5		13±0.5	
e	f	g		
21 <sup>±1.0</sup>	2.0±0.5	2.0 <sup>±0.5</sup>		

## Direction of product insertion



[Packing: 3 000pcs/reel]



## 2. 750pcs/reel

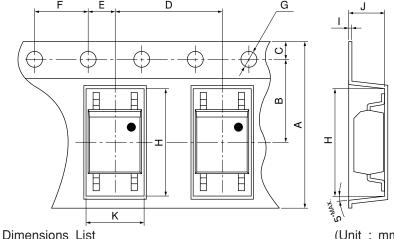
## Package materials

Carrier tape: A-PET (with anti-static material)

Cover tape: PET (three layer system)

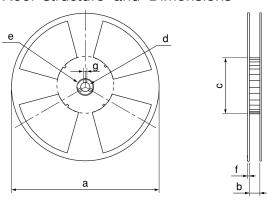
Reel: PS

## Carrier tape structure and Dimensions



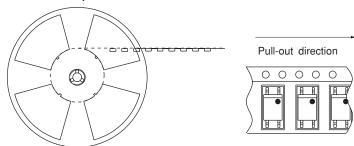
Dimensions List						(Offic a fillin)		
A	В	С	D	Е	F	G		
12.0±0.3	5.5 <sup>±0.1</sup>	1.75 <sup>±0.1</sup>	8.0 <sup>±0.1</sup>	2.0 <sup>±0.1</sup>	4.0 <sup>±0.1</sup>	φ1.5 <del>+</del> 0.1		
Н	I	J	K					
$7.4^{\pm0.1}$	0.3 <sup>±0.05</sup>	3.1 <sup>±0.1</sup>	4.0 <sup>±0.1</sup>					

## Reel structure and Dimensions



Dimensio	ns List	(Unit: mm)			
a	b	С	d		
180	180 13.5±1.5 e f 21±1.0 2.0±0.5		13 <sup>±0.5</sup>		
e					
21±1.0					

## Direction of product insertion



[Packing: 750pcs/reel]



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  - --- Test and measurement equipment
  - --- Industrial control
  - --- Audio visual equipment
  - --- Consumer electronics
- (ii) Measures such as fail-safe function and redundant design should be taken to ensure reliability and safety when SHARP devices are used for or in connection

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- --- Traffic signals
- --- Gas leakage sensor breakers
- --- Alarm equipment
- --- Various safety devices, etc.
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[E194] Sheet No.: D2-A00202EN